



New Concepts for Reliable Low-Cost Module Encapsulation and Barrier Technologies

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 Stanford University

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*SLAC National Laboratory, † Lawrence Livermore National Laboratory

December 2019



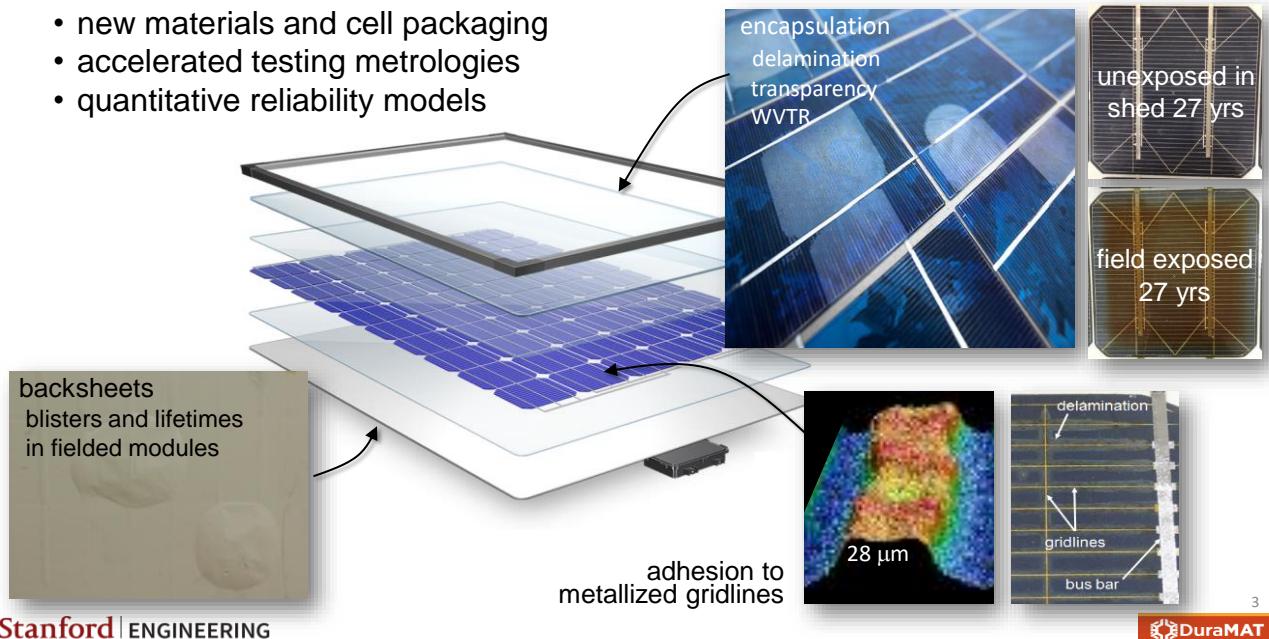
Outline

Scope: industrially-relevant new concepts in solar module encapsulation and moisture barrier technologies to accelerate state-of-the-art module performance, reliability and manufacturability with new module materials and interfaces demonstrated using accelerated testing and reliability models.

- Thrust 1: Encapsulant Degradation Mechanisms
 - Wide Angle X-ray Scattering and FTIR-ATR of delaminated EVA (with SLAC)
 - understanding and modeling fundamental degradation pathways
- Thrust 2: Advanced In-Situ Moisture Barrier Technology
 - open-air plasma-deposition of submicron multilayer barrier films
 - improved moisture barrier properties under accelerated aging conditions

Innovating Module Materials and Metrologies for Reliability

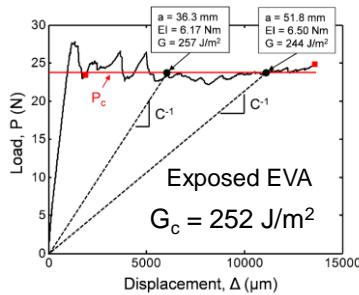
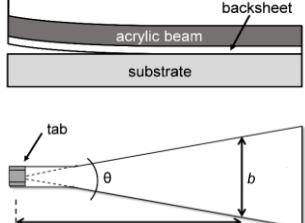
- new materials and cell packaging
- accelerated testing metrologies
- quantitative reliability models



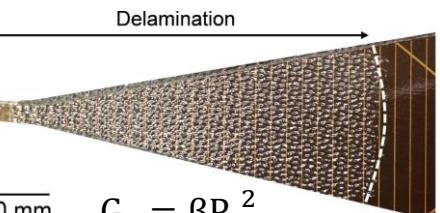
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Interfacial Adhesion Metrology for Solar Module Materials

Encapsulation Delamination



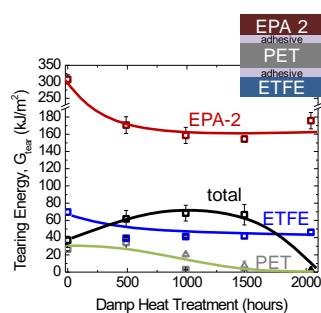
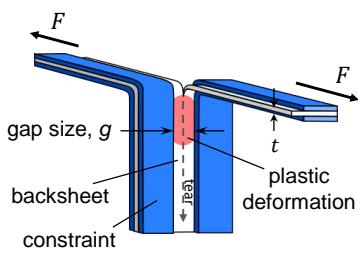
Tracy, Bosco, Novoa, Dauskardt, Prog. Photovoltaics: Res. App., 2017.



$$G_c = \beta P_c^2$$

$$\beta = \frac{\Delta_i}{P_c} \left(\frac{1}{ka_i^2} \right)$$

Backsheets



Yuen, Moffitt, Novoa, Schelhas, Dauskardt, Prog. in Photovoltaics, 2019.

EPA 1

PET

b

g_{delam}

$$G_{\text{tear}}^{\text{total}} = (G_{\text{surface}} + w_p \cdot b)_{\text{EPA}} \cdot \frac{t_{\text{EPA}}}{t_{\text{tot}}} + G_{\text{tear,PET}} \cdot \frac{t_{\text{PET}}}{t_{\text{tot}}} + G_{\text{delam}} \cdot \frac{g_{\text{delam}}}{t_{\text{tot}}}$$

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DuraMAT

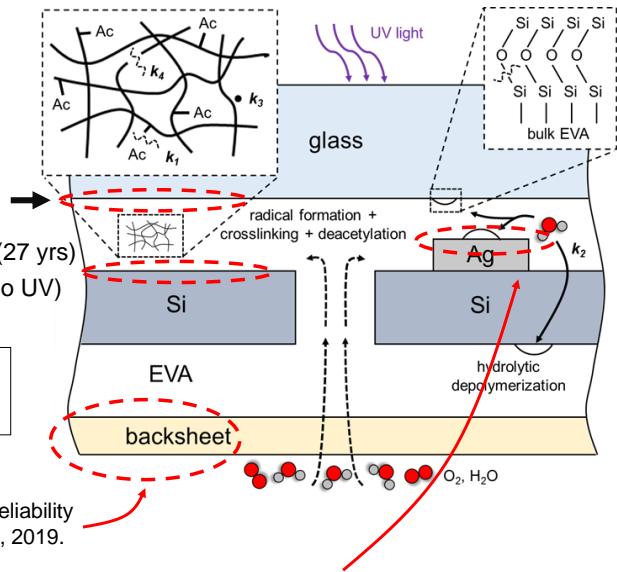
Degradation Mechanisms of Bulk Encapsulant and Interfaces

synergistic environmental stressors:

- sunlight (UV)
- heat
- humidity
- electrical bias (ion migration)
- thermomechanical strains

$$G_c \approx 1,750 \text{ J/m}^2 \text{ to } 250 \text{ (27 yrs)} \\ \dots \text{or to } 1,170 \text{ (27 yrs no UV)}$$

What are the detailed encapsulation degradation mechanisms?



Yuen, Moffitt, Novoa, Schelhas, Dauskardt, "Tearing and reliability of photovoltaic module backsheets," *Prog. Photovoltaics*, 2019.

Tracy, Bosco, Dauskardt, "Evaluation of Encapsulant Adhesion to Surface Metallization of Photovoltaic Cells," *IEEE J. Photovoltaics*, 2017.

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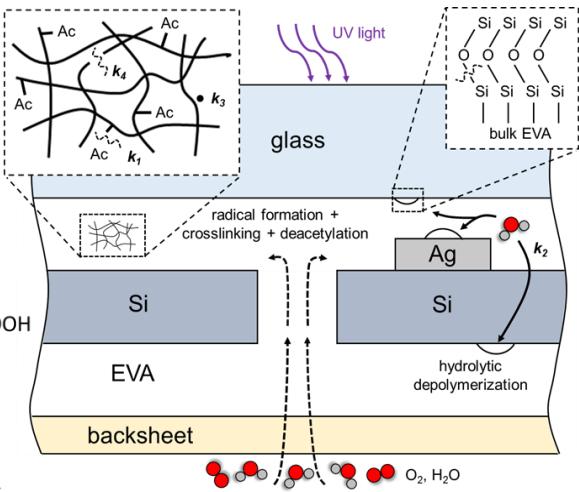
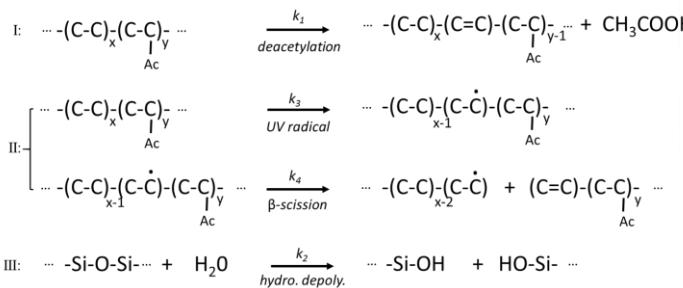


Degradation Mechanisms of Bulk Encapsulant and Interfaces

synergistic environmental stressors:

- sunlight (UV)
- heat
- humidity
- electrical bias (ion migration)
- thermomechanical strains

specific EVA degradation reactions:



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Tracy, D'hooge, Bosco, Delgado, Dauskardt, Prog. in Photovoltaics, 2018.



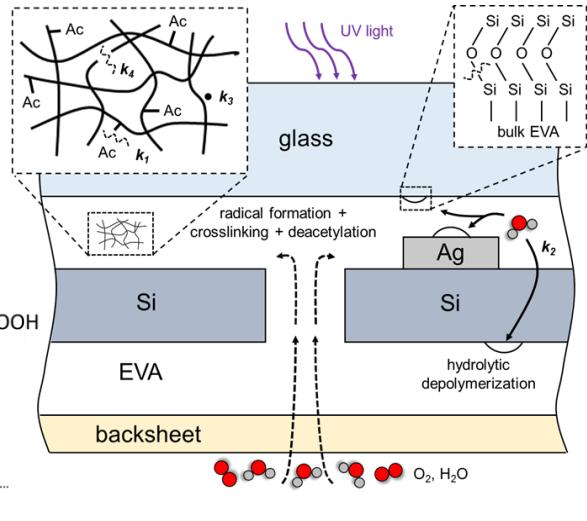
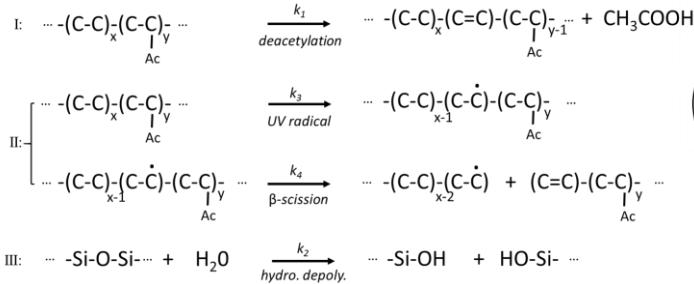
Degradation Mechanisms of Bulk Encapsulant and Interfaces

analytical adhesion mechanics model

$$G_c(t) = \sum_i^n G_{c,intr,i}(t) + G_{c,PL}(t)$$

intrinsic contribution non-linear contribution

specific EVA degradation reactions:



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Degradation Mechanisms of Bulk Encapsulant and Interfaces

analytical adhesion mechanics model

$$G_c(t) = \sum_i^n G_{c,intr,i}(t) + G_{c,PL}(t)$$

intrinsic contribution non-linear contribution

- depends on bond rupture
- decreases with bond rupture events
- superposition of i processes

$$G_{c,intr,i}(t) = G_{c,intr,i}(0)f_i(t)$$

$$f_i(t) = \exp\left(-a_i\left(1 - \frac{b_i(t)}{b_i(0)}\right)\right)$$

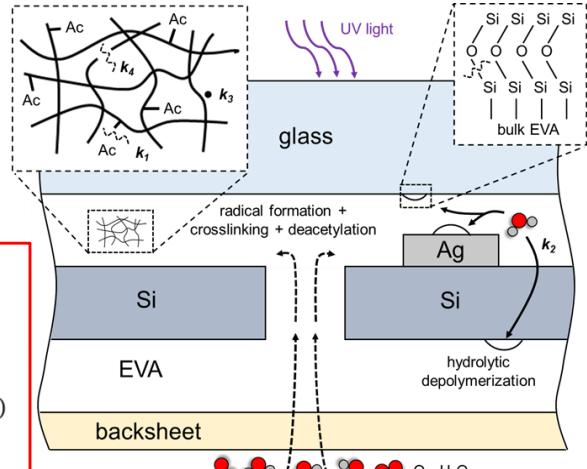
intensity factor bonds rupture ratio

- viscoelastic deformation that accompanies bond breakage
- decreases proportionally with intrinsic contribution

$$G_{c,PL}(t) = \sum_i^n G_{c,intr,i}(t) d(t)$$

$$d(t) = d(0) \left(1 - \frac{t}{t_\infty}\right)$$

proportionality factor



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Tracy, D'hooge, Bosco, Delgado, Dauskardt, Prog. in Photovoltaics, 2018.

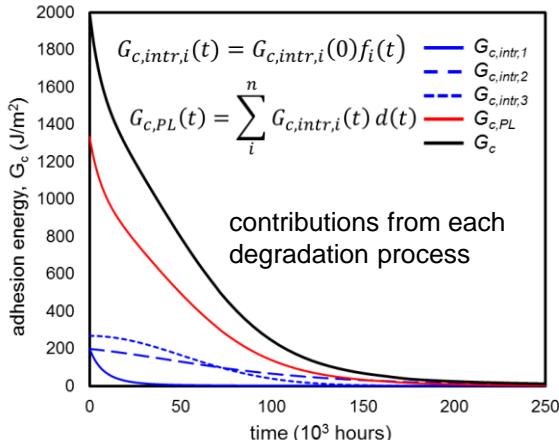


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Degradation Mechanisms of Bulk Encapsulant and Interfaces

analytical adhesion mechanics model

$$G_c(t) = \sum_i^n G_{c,intr,i}(t) + G_{c,PL}(t)$$



$$f_i(t) = \exp\left(-a_i\left(1 - \frac{b_i(t)}{b_i(0)}\right)\right) \quad k_j = A_j \exp\left(-\frac{E_{A,j}}{RT}\right)$$

$$\frac{dc_{VAc}(t)}{dt} = -k_1 c_{VAc}(t) \quad \text{deacetylation (I)}$$

$$\frac{b_1(t)}{b_1(0)} = \exp(-k_1 t)$$

$$\frac{dc_{SiOSi}(t)}{dt} = -k_2 c_{SiOSi}(t)c_w(t) \quad \text{hydr. depolym. (III)}$$

$$\frac{b_2(t)}{b_2(0)} = \exp(-k_2 c_{w,eq} t)$$

$$\frac{dc_{MCR}(t)}{dt} = k_3 \mu_1 - k_4 c_{MCR}(t) \quad \text{radical formation and scission (II)}$$

$$\frac{dc_{MM}(t)}{dt} = k_4 c_{MCR}(t)$$

$$1 - \frac{b_3(t)}{b_3(0)} = \frac{c_{CL}(t)}{c_{CL}(0)} = \frac{k_3 \mu_1}{c_{CL}(0)} \left(t - \left(\frac{1}{k_4} + c_{MCR}(0) \right) (1 - \exp(-k_4 t)) \right)$$

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Tracy, D'hooge, Bosco, Delgado, Dauskardt, Prog. in Photovoltaics, 2018.

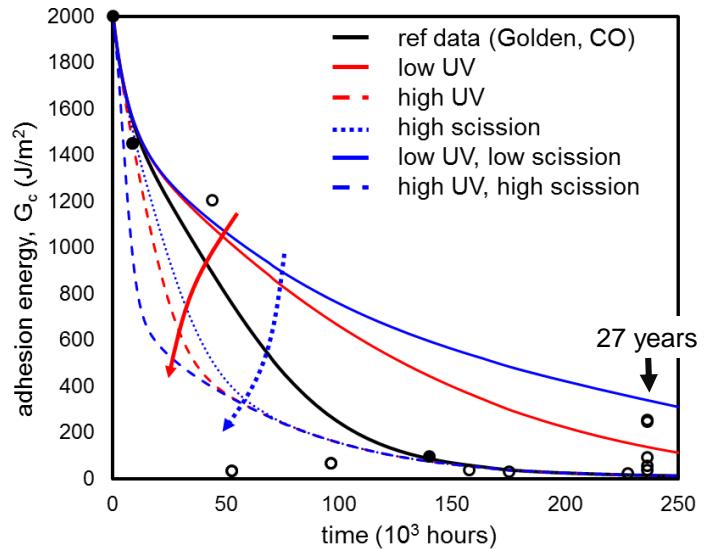


Predictive Modelling for Adhesion Degradation

deacetylation UV radicals + scission hydrolytic depolymerization

Sensitivity of adhesion to individual degradation processes varies temporally:

- deacetylation dominates initially
- UV radical formation and scission dominate at intermediate timeframes
- interface hydrolysis dominates at $t > 10$ yrs

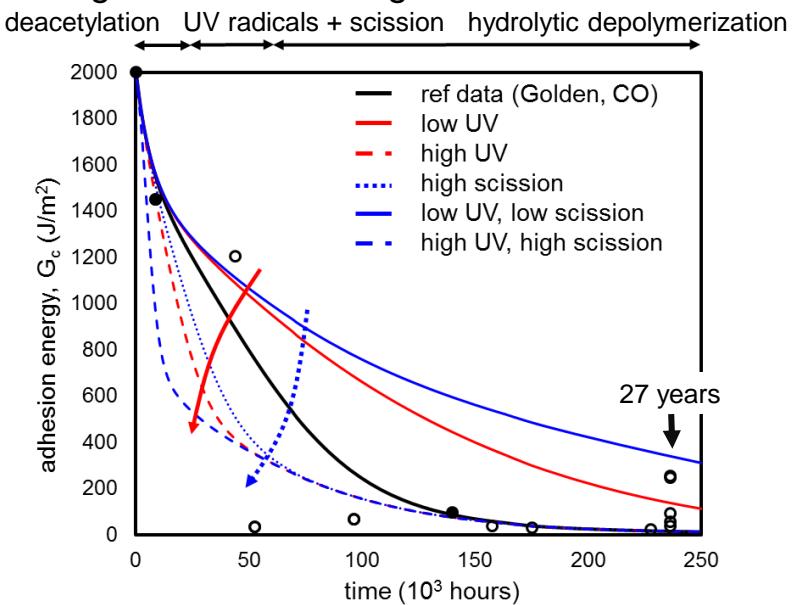
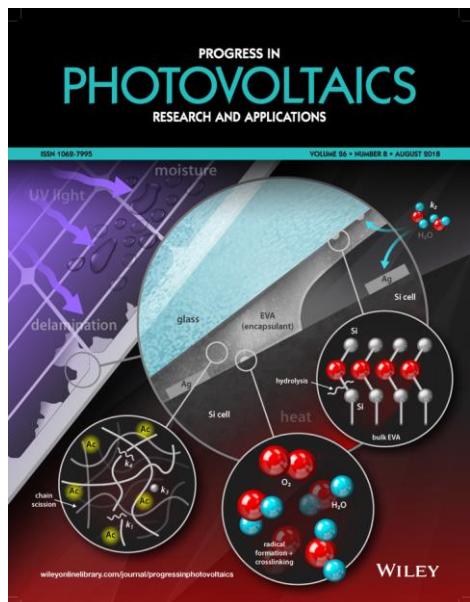


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Predictive Modelling for Adhesion Degradation



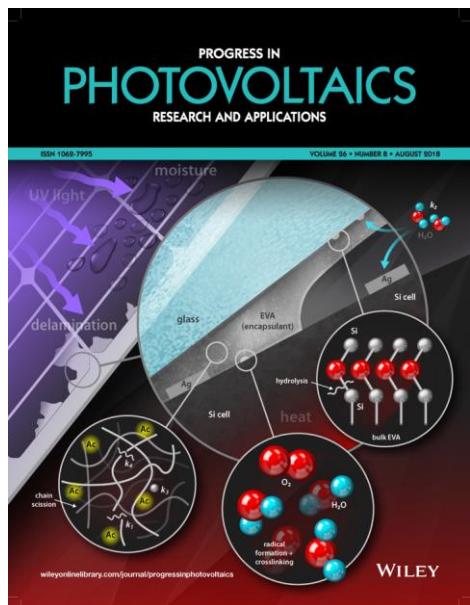
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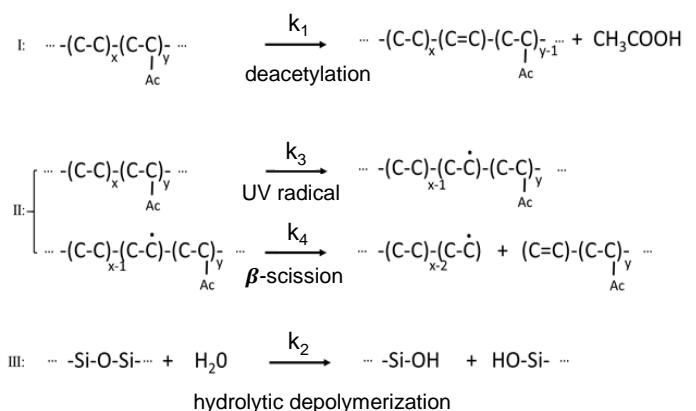


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Modular Description of Critical Degradation Pathways in EVA



Degradation Pathways



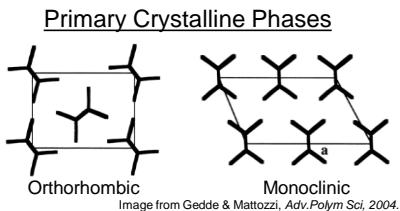
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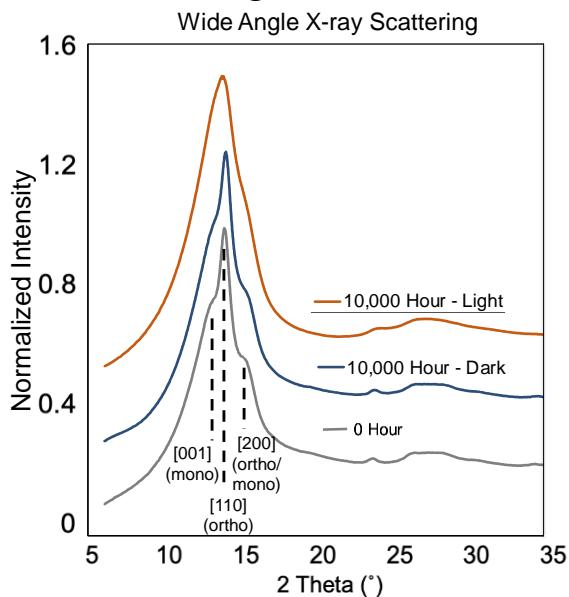
Advanced Characterization of EVA Degradation: WAXS

EVA is a semi-crystalline polymer...



- crystalline vol. frac. ~ 5%
- remainder amorphous

—Exposure Conditions—
10,000 Hours
"Dark" – 85°C, 13.5%RH, No UV,
"Light" – 65°C, 30%RH,
with UV: 81 W/m²



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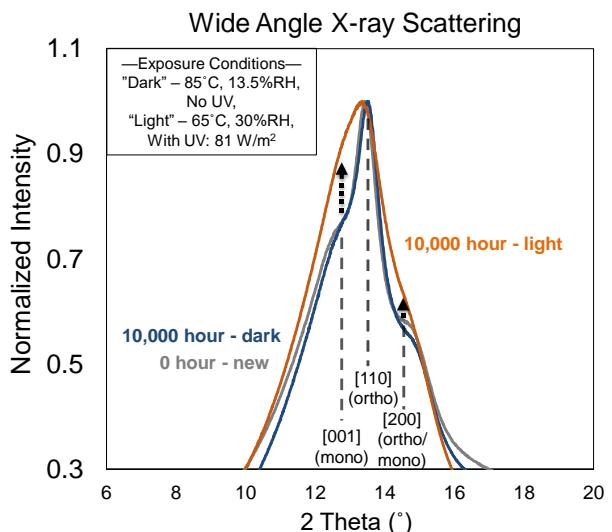
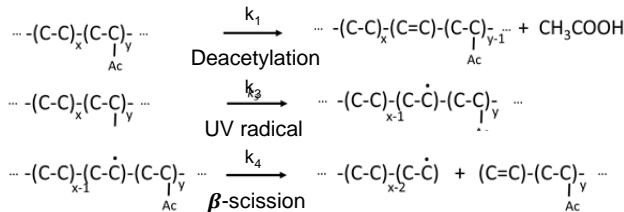
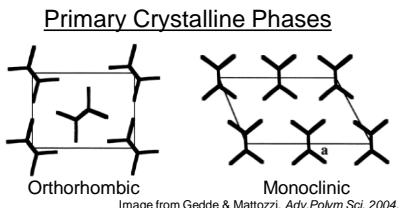
With Laura Schelhas and Stephanie Moffitt, SLAC



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Advanced Characterization of EVA Degradation: WAXS

EVA is a semi-crystalline polymer...



Monoclinic crystallites form from shorter ethylene segments. The comparative increase of monoclinic phase evidences main chain degradation.

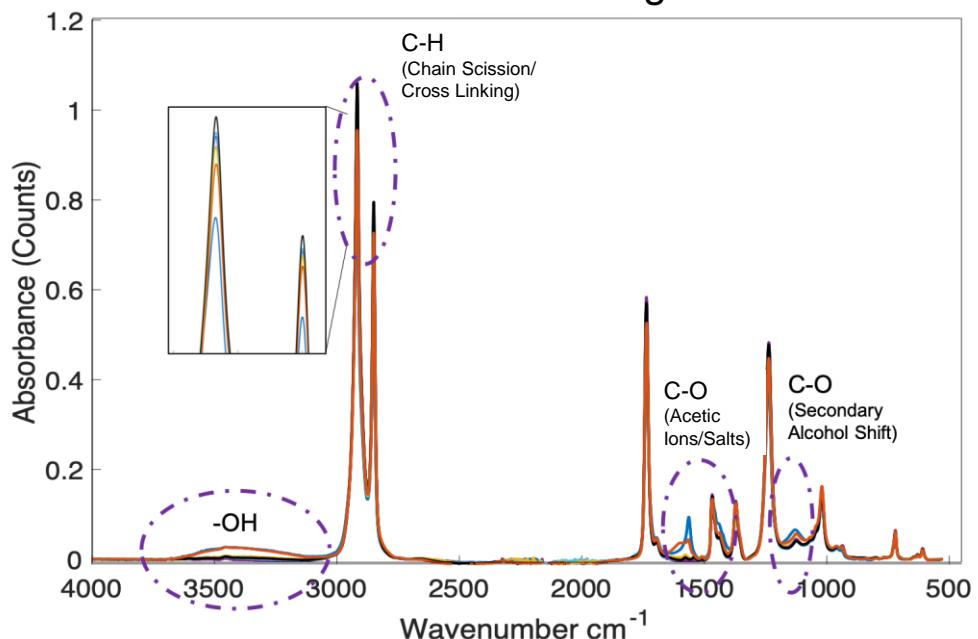
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Advanced Characterization of EVA Degradation: FTIR-ATR

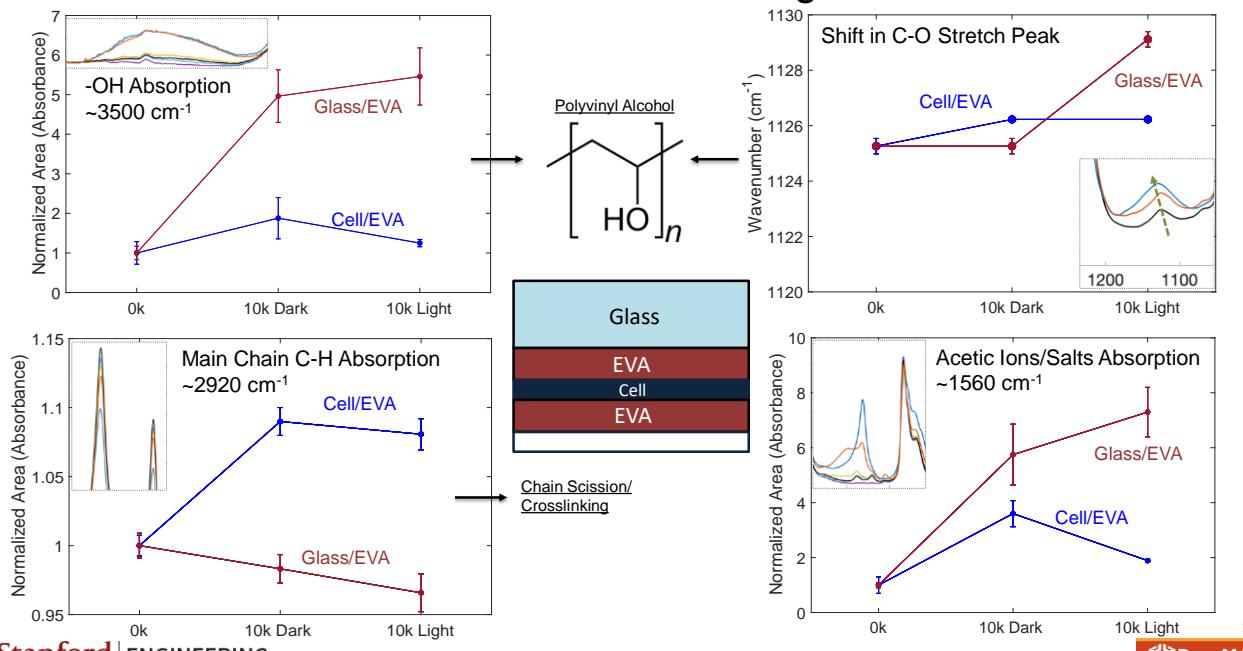


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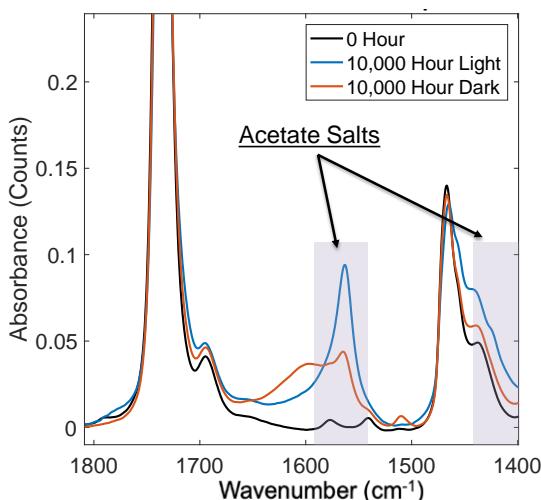
Advanced Characterization of EVA Degradation: FTIR-ATR



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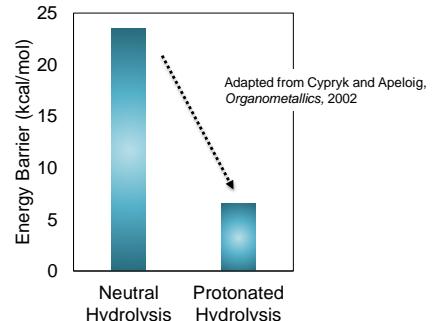
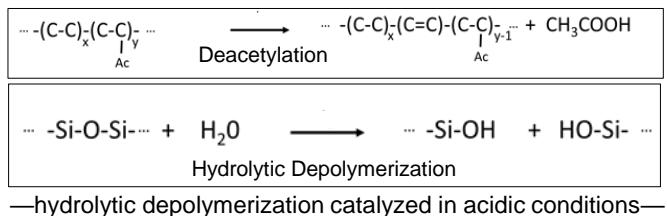


FTIR-ATR: Interdependencies of Degradation Pathways



Location of key C-O stretching bands for Acetate Ions/Salts¹:

- i. symmetric stretch – 1415 ± 20
- ii. antisymmetric stretch – 1570 ± 20
- i. low concentrations of acetate \rightarrow weak split peaks at 1560 and 1577
- ii. high concentrations of acetate \rightarrow peaks merge and give higher intensity



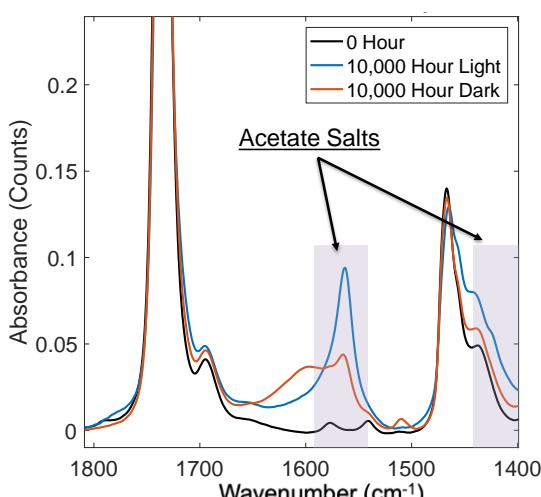
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1 - Wang & Golden, *International Journal of Electrochemistry*, 2013.

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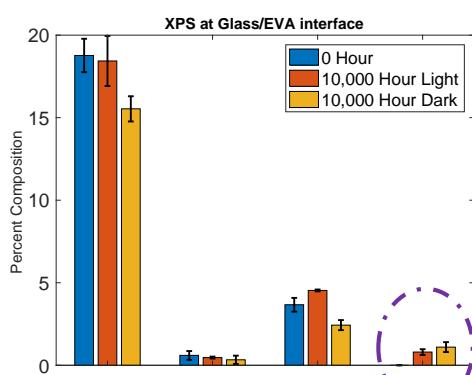
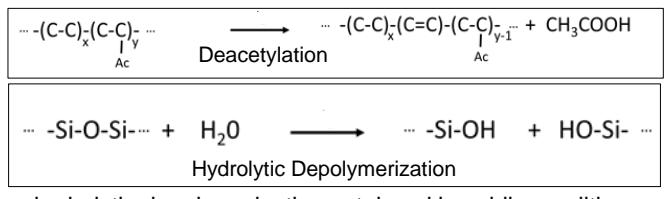


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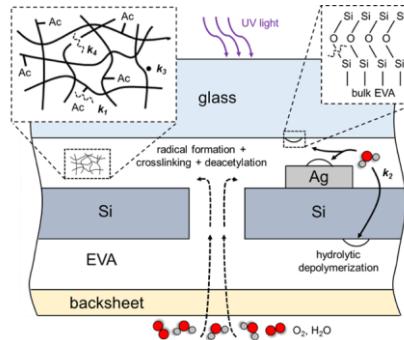
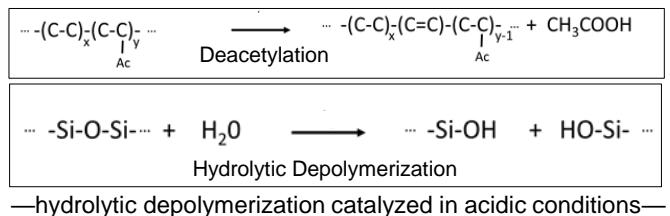
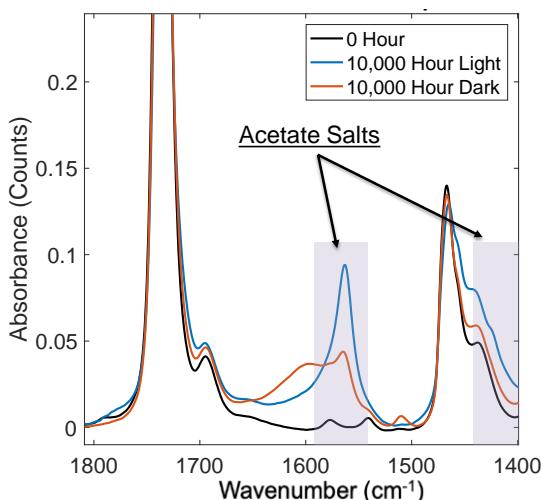


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FTIR-ATR: Interdependencies of Degradation Pathways



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Outline

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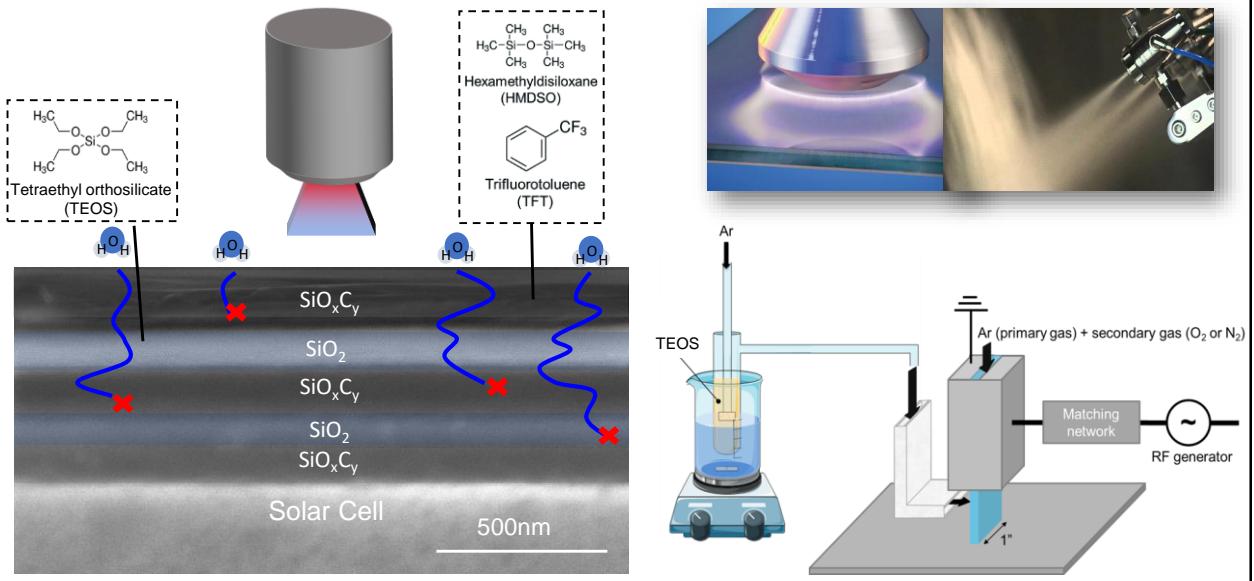
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Open-Air Spray Plasma Processing of In-Situ Barrier Films

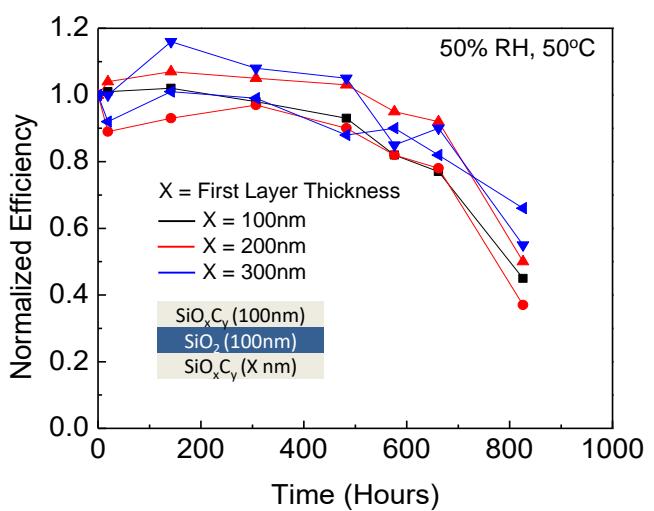
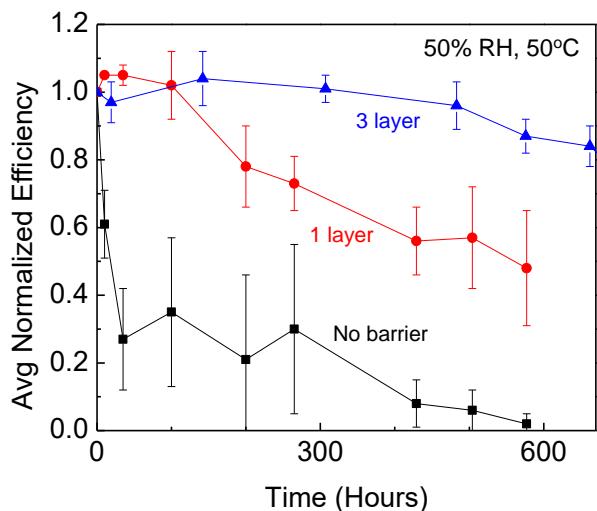


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Barrier Layers Markedly Improves Device Stability

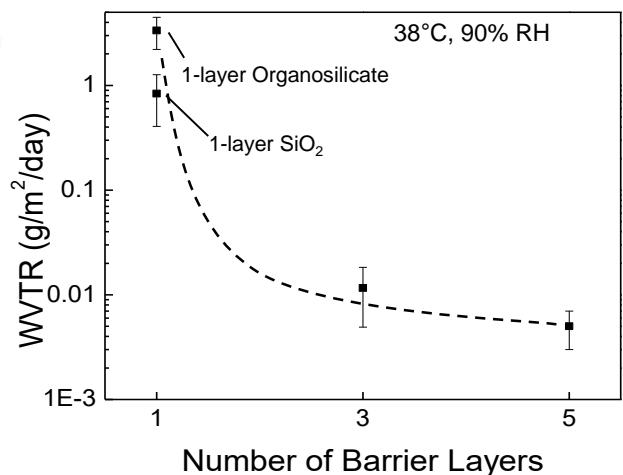
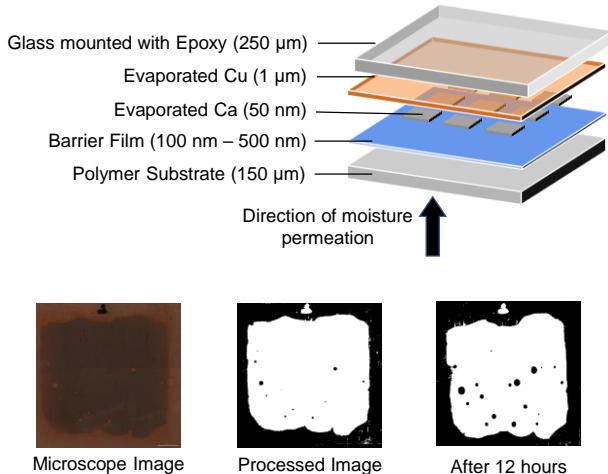


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Barrier Properties – WVTR by Calcium Test



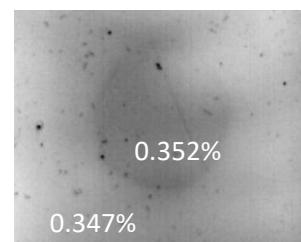
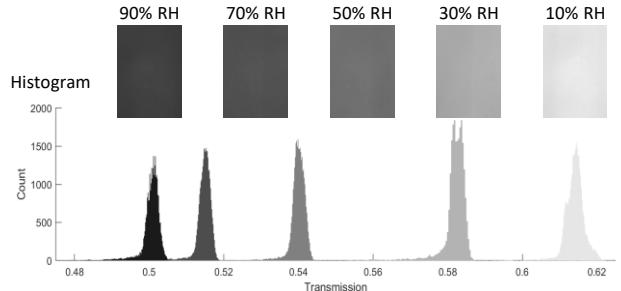
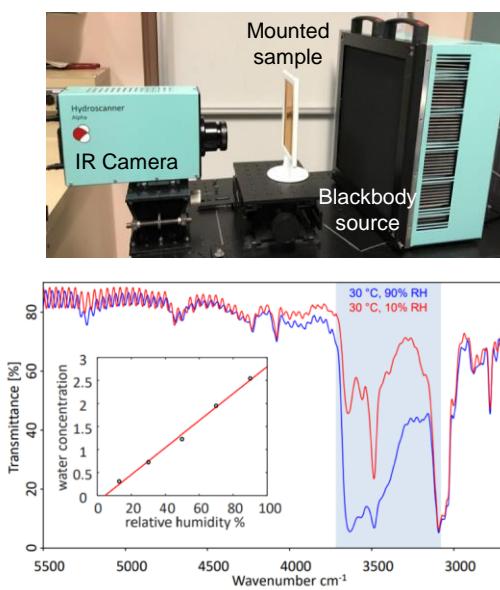
5-layer barrier has a WVTR of 5.92×10^{-3} g/m²/day which is more than 2 orders of magnitude lower than a single layer organosilicate barrier.

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Barrier Properties – Moisture Transmission by IR Imaging



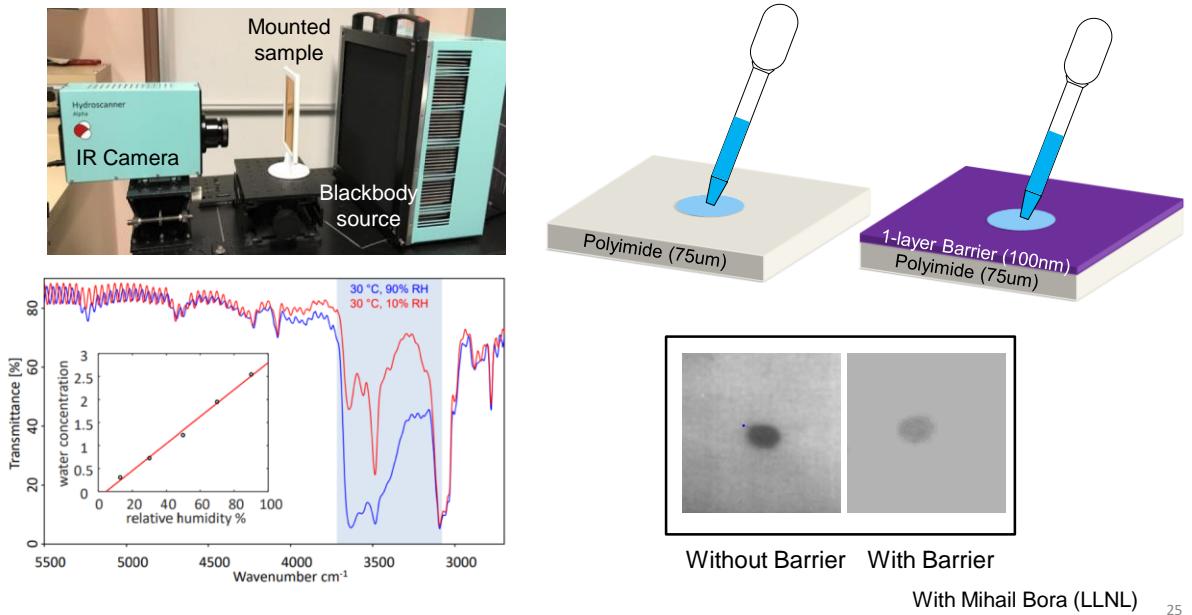
With Mihail Bora (LLNL)

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Barrier Properties – Moisture Transmission by IR Imaging



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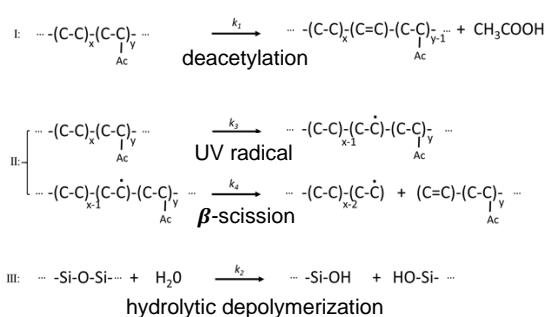


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Conclusion: New Concepts in Module Reliability

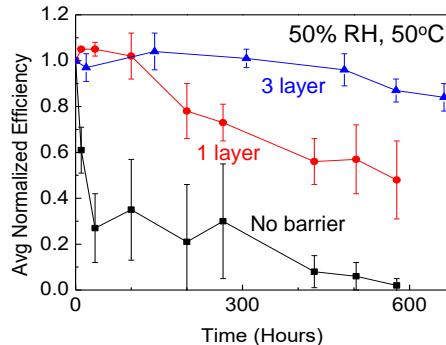
Scope: industrially-relevant new concepts in solar module encapsulation and moisture barrier technologies to accelerate state-of-the-art module performance, reliability and manufacturability with new module materials and interfaces demonstrated using accelerated testing and reliability models.

Thrust 1: Encapsulant Degradation Mechanisms



High resolution WAXS and FTIR-ATR explain the presence and interdependencies of degradation pathways.

Thrust 2: Open-air In-Situ Moisture Barriers



Low-cost barrier layers significantly improves solar cell stability in humid environments.

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Future Directions – Advancing Bifacial Modules

Advancing Bifacial Solar Module Reliability and Manufacturability with New Module Materials and Light-Weight Transparent Back Lamination

Emergence of Bifacial PV: Bifacial panels have significant advantages over mono-facial modules with increased power yield by up to 30%, and costs for bifacial PERC production are within \$0.01—0.02/W of the costs for mono-facial PERC production*.

Builds directly on capabilities developed in our current DuraMAT program, include advanced characterization and modeling of fundamental degradation pathways in module encapsulation materials and our advanced in-situ moisture barrier technology.

Leverages the DuraMAT Materials Characterization and Forensics capability through our continued partnership with SLAC and collaboration with Dr. Matt Reese on WVTR characterization and Dr. Mike Woodhouse at NREL involving bifacial techno-economic analyses useful for U.S. PV manufacturing.

Thrust 1 - Bifacial module materials degradation and interface reliability characterization.

Thrust 2 – Develop and validate a transparent polymer back lamination technology comprising 1) a conformal, dense, multi-dyad thin-film barrier structure deposited directly onto the module backside using a scalable open-air spray plasma for pin-hole free barriers, 2) a high-quality transparent encapsulate, and 3) transparent polymer backsheet containing fluoropolymer which provides robust mechanical protection.

